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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Abadeer, et al.

Serial No.: 10/063,295

Filing Date: April 9, 2002

For: SYSTEM AND METHOD FOR MEASURING CIRCUIT PERFORMANCE
DEGRADATION DUE TO PFET NEAGATIVE BI TEMPERATURE
INSTABILITY (NBTI)



Attorney Docket No.: BUR920010127US1

Group Art Unit: 2817

Examiner: Shingleton, Michael B.

ATTN: Mail Stop Issue Fee
Honorable Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUBMISSION OF REPLACEMENT FORMAL DRAWINGS

Sir:

In response to the Notice of Drawing Inconsistency with Specification dated February 25, 2004, submitted herewith is a full set of replacement formal drawings for Figures 1-20 for the above-identified patent application. The replacement set is a duplicate set of the drawings filed on June 12, 2002, therefore, no substantive changes in the drawings have been made.

Applicant disagrees that there are inconsistencies between the drawings and specification, and maintains that Figures 8A and 8B on replacement sheets 6 and 7, respectively, are clearly listed in the Brief Description of the Drawings of the specification at page 11, lines 12-16.

Approval and acknowledgment of receipt are respectfully requested.

Respectfully submitted,

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Date: 3/15/04

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